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SERIAL NUMBER 10/542,873	FILING OR 371(c) DATE 07/20/2005 RULE	CLASS 324	GROUP ART UNIT 2829	ATTORNEY DOCKET NO. 5731-000014/US/NP
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## APPLICANTS

Beng Ghee Tan, Singapore, SINGAPORE; *AV*

## \*\* CONTINUING DATA \*\*\*\*\*

This application is a 371 of PCT/SG03/00022 02/05/2003 *AV*

## \*\* FOREIGN APPLICATIONS \*\*\*\*\*

*AV*

Foreign Priority claimed	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no	STATE OR COUNTRY SINGAPORE	SHEETS DRAWING 5	TOTAL CLAIMS 17	INDEPENDENT CLAIMS 2
35 USC 119 (a-d) conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged	<i>AV</i>	Examiner's Signature <i>AV</i>	Initials		

## ADDRESS

28997

## TITLE

Method for detecting and monitoring wafer probing process instability

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